Flom Test Labs
EMI, EMC, RF Testing Experts Since 1963
toll-free: (866) 311-3268
fax: (480) 926-3598
http://www.flomlabs.com
info@flomlabs.com

Date: March 31, 2009

Applicant: Novatel Wireless Inc.
9645 Scranton Rd, Suite 205
San Diego, CA 92121

Attention of: John Spall, Project Manager
Ph: 858-812-0697
Fax: 858-450-7183
email: jspall@nvtl.com

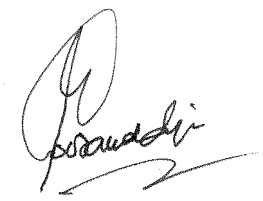
Equipment: PKRNVWE760D co located with PPD-AR5BHB92
FCC ID: PKRNVWE760D
FCC Rules: Radio Frequency Radiation Exposure Limits
47 CFR 1.1310
MPE - Mobiles X Fixed Based Station _____

Gentlemen:

Enclosed please find your copy of the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

Please allow from 8-12 weeks to hear from the Commission, who may request additional data or information, and even a sample for pre-grant audit testing.

Should you need any clarification, just fax or phone. Thank you again for this order - it has been a pleasure to be of service.



Supervised By: Hoosamuddin S. Bandukwala, Lab Director

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Date: March 31, 2009

Federal Communications Commission
Via: Electronic Filing

Attention: Authorization & Evaluation Division

Applicant: Novatel Wireless Inc.
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FCC ID: PKRNVWE760D
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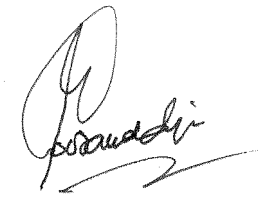
47 CFR 1.1310
MPE - Mobiles X Fixed Based Station _____

Gentlemen:

On behalf of the Applicant, enclosed please find the Supplemental Test Data Report, the whole for Environmental Assessment (MPE) of the referenced equipment as shown.

We trust the same is in order. Should you need any further information, kindly contact the writer who is authorized to act as agent.



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Environmental Assessment

for

Mobiles

for

FCC ID: PKRNVWE760D

Model: PKRNVWE760D co located with PPD-AR5BHB92

to

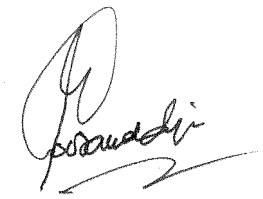
Federal Communications Commission

47 CFR 1.1310

Radio Frequency Radiation Exposure Limits

Date Of Report: March 31, 2009

On the Behalf of the Applicant:	Novatel Wireless Inc.
At the Request of:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121
Attention of:	John Spall, Project Manager Ph: 858-812-0697 Fax: 858-450-7183 email: jspall@nvtl.com



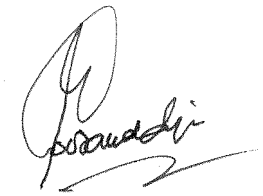
Supervised By: Hoosamuddin S. Bandukwala, Lab Director

Revision History

Revision	Date	Revised By	Reason for revision
1.0	March 31, 2009	H Bandukwala	Original Document

Table of Contents

Required information per ISO 17025-2005, paragraph 5.10:

a)	**Test Report (Supplemental)**
b) Laboratory: (FCC: 31040/SIT) (Canada: IC 2044)	Flom Test Labs 3356 N. San Marcos Place, Suite 107 Chandler, AZ 85225
c) Report Number:	d0930028
d) Client:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121
e) Identification: Description:	PKRNVWE760D co located with PPD-AR5BHB92 Laptop Computer Studio 1737 - Pacino/Montevina
f) EUT Condition:	Not required unless specified in individual tests.
g) Report Date:	March 31, 2009
h, j, k):	As indicated in individual tests.
i) Sampling method:	No sampling procedure used.
l) Uncertainty:	In accordance with FTL internal quality manual.
m) Supervised by:	 Hoosamuddin S. Bandukwala, Lab Director
n) Results:	The results presented in this report relate only to the item tested.
o) Reproduction:	This report must not be reproduced, except in full, without written permission from this laboratory.

Identification of the Equipment Under Test (EUT)

Name and Address of Applicant:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121
Manufacturer:	Novatel Wireless Inc. 9645 Scranton Rd, Suite 205 San Diego, CA 92121
FCC ID:	PKRNVWE760D
Model Number:	Studio 1737 - Pacino/Montevina
Description:	Class II Permissive
Type of Emission:	CDMA
Frequency Range, MHz:	824.7 – 848.31, 1851.25 – 1908.75
Power Rating, Watts:	0.877

____ Switchable ____ Variable X N/A

Modulation:

____ AMPS
____ TDMA
X CDMA
X OTHER

Antenna:

____ Helical
____ Monopole
____ Whip
X Other

Note: For RF Safety test antenna gain taken at the upper range of expected gain (i.e. 0 dBd) and RF Power set to highest nominal power across all channels.

A2LA

"A2LA has accredited Flom Test Labs, Inc. Chandler, AZ for technical competence in the field of Electrical testing. The accreditation covers the specific tests and types of tests listed on the agreed scope of accreditation. This laboratory meets the requirements of ISO 17025:2005 'General Requirements for the Competence of Testing and Calibration Laboratories' and any additional program requirements in the identified field of testing."

Please refer to www.a2la.org for current scope of accreditation.

Certificate number: 2152.01

Standard Test Conditions and Engineering Practices

Except as noted herein, the following conditions and procedures were observed during the testing:

In accordance with ANSI C63.4-2004 and unless otherwise indicated in the specific measurement results, the ambient temperature of the actual EUT was maintained within the range of 10° to 40°C (50° to 104 °F) unless the particular equipment requirements specify testing over a different temperature range. Also, unless otherwise indicated, the humidity levels were in the range of 10% to 90% relative humidity.

Prior to testing, the EUT was tuned up in accordance with the manufacturer's alignment procedures. All external gain controls were maintained at the position of maximum and/or optimum gain throughout the testing.

Measurement results, unless otherwise noted, are worst-case measurements.

Name of Test:	Environmental Assessment	
Specification:	FCC: 47 CFR 1.1310	
Measurement Guide:	ANSI/IEEE C95.1 1992	
Name of Test:	R.F. Radiation Exposure	
FCC Rules:	1.1307, 1.1310, 1.1311, 2.1091	
Limits: Uncontrolled Exposure	0.3-1.234 MHz:	Limit [mW/cm^2] = 100
47 CFR 1.1310	1.34-30 MHz:	Limit [mW/cm^2] = ($180/f^2$)
Table 1, (B)	30-300 MHz:	Limit [mW/cm^2] = 0.2
	300-1500 MHz	Limit [mW/cm^2] = f/1500
	1500-100,000 MHz:	Limit [mW/cm^2] = 1.0

Test Frequencies, MHz	824 – 848
Power, Conducted, mW	= 877
Antenna Gain	= 1.22 dBi
Antenna Model	Metal, Modified Planer Inverted F Antenna
Distance cm	20
Limit Calculations	$Limit_{[mW/cm2]}$ = 0.549

Test Frequencies, MHz	1851 - 1908
Power, Conducted, mW	= 628
Antenna Gain	= 1.63 dBi
Antenna Model	Metal, Modified Planer Inverted F Antenna
Distance cm	20
Limit Calculations	$Limit_{[mW/cm2]}$ = 1.0

PKRNVWE760D CDMA

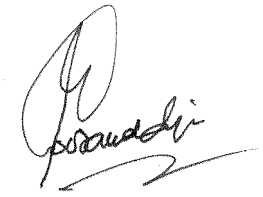
CDMA Frequency MHz	TX Power (m)W	Duty Cycle (%)	Power Density (mW/cm^2)	Limit (mW/cm^2)	Result
824 – 848	877	25	0.057	0.549	Pass
1851 - 1908	628	25	0.045	1.0	Pass

PPD-AR5BHB92 802.11

802.11 Frequency MHz	TX Power (mW)	Power Density (mW/cm^2)	Limit (mW/cm^2)	Result
2412 - 2462	0.907	0.360	1.0	Pass
2422 - 2452	0.310	0.123	1.0	Pass
5745 - 5825	0.833	0.331	1.0	Pass
5755 - 5795	0.965	0.391	1.0	Pass

PKRNVWE760D CDMA Collocated with PPD-AR5BHB92 802.11

CDMA Frequency MHz	802.11 Frequency MHz	CDMA Power Density (mW/cm^2)	802.11 Power Density (mW/cm^2)	Total Power Density (mW/cm^2)	Limit (mW/cm^2)	Result
824 – 848	2412 - 2462	0.057	0.360	0.417	0.549	Pass
824 – 848	2422 - 2452	0.057	0.123	0.18	0.549	Pass
824 – 848	5745 - 5825	0.057	0.331	0.388	0.549	Pass
824 – 848	5755 - 5795	0.057	0.391	0.448	0.549	Pass
1851 - 1908	2412 - 2462	0.045	0.360	0.405	1.0	Pass
1851 - 1908	2422 - 2452	0.045	0.123	0.168	1.0	Pass
1851 - 1908	5745 - 5825	0.045	0.331	0.376	1.0	Pass
1851 - 1908	5755 - 5795	0.045	0.391	0.436	1.0	Pass

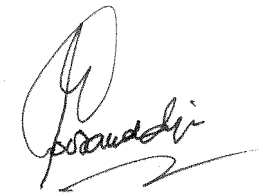


Supervised By: Hoosamuddin S. Bandukwala, Lab Director

Testimonial
and
Statement of Certification

This is to certify that:

1. **That** the application was prepared either by, or under the direct supervision of, the undersigned.
2. **That** the technical data supplied with the application was taken under my direction and supervision.
3. **That** the data was obtained on representative units, randomly selected.
4. **That**, to the best of my knowledge and belief, the facts set forth in the application and accompanying technical data are true and correct.



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